Issue Classification



Applicati	ion/Con	trol No.
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10709508

CHENG ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Art Unit

Connolly, Mark

2115

ORIGINAL				INTERNATIONAL CLASSIFICATION											
CLASS S			SUBCLASS	CLASS CLAIMED				LAIMED	NON-CLAIMED						
713			322			G	0	6	F	1 / 00 (20	06.0)				
CROSS REFERENCE(S)				G	0	6	F	1 / 32 (2006.0	1.01)						
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Connolly, Mark (Assistant Examiner) (Date) 7/26/07		SUF	THOMAS LEE ERVISORY PATENT EXAMINED ECHNOLOGY CENTER 2100					IINE:	Total Claims Allowed:						
(Legal Instruments (Date)			1	Momenta plils					4115)	O.G. Print Claim(s)			O.G. Print Figure		
(Legal Instruments (Date) Examiner)			(Primary Examiner) (Date)					Date)	1				4		